Supporting Information

Substrate-determined shape ...

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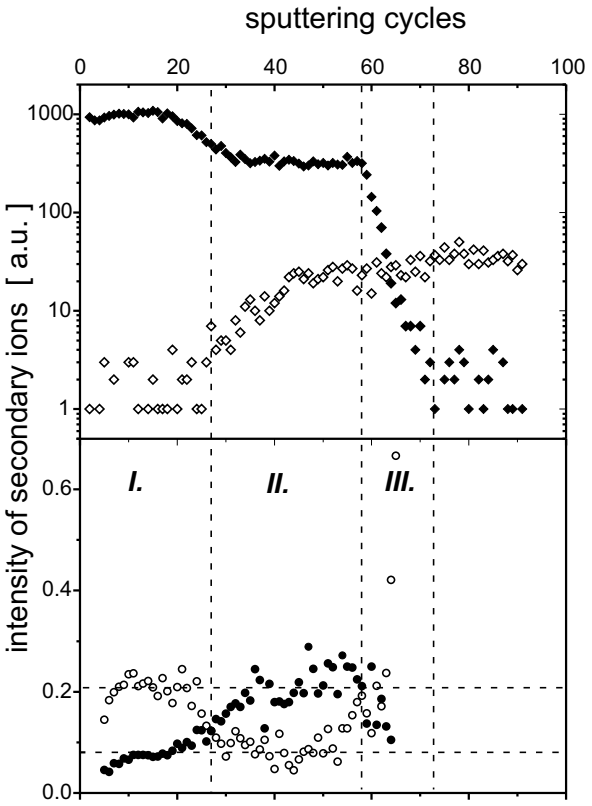

Fig. S1. Vertical domain structure of the dPS_2/PI_1 film on CH_3-SAM as determined with profiling dSIMS mode (1 cycle ~ 3.5 nm). Symbols, dashed lines and sputtering periods as in Fig. 5. Note, that identical vertical domain structure was determined for the dPS_2/PI_1 on COOH-SAM (cf. Fig. 5) and for dPS_2/PI_2 on SiO_X (cf. Fig. S2)

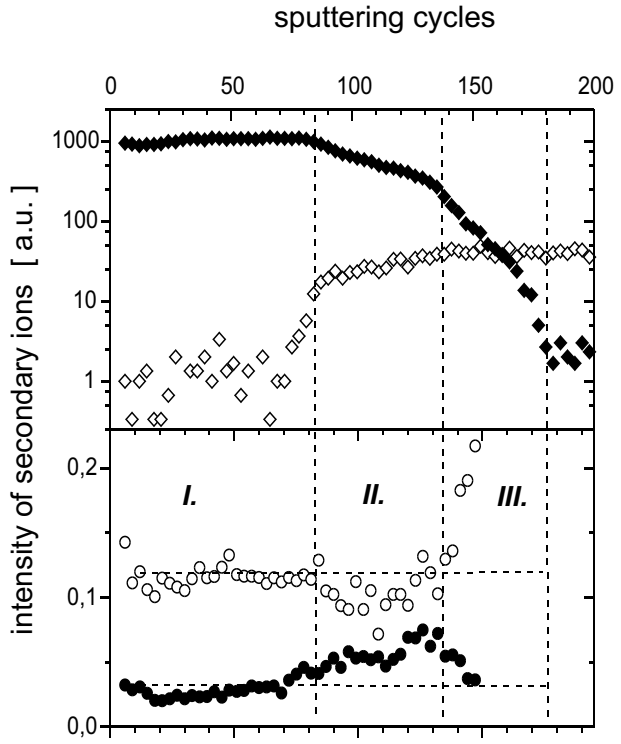

Fig. S2. As Fig. S1 but for the dPS_2/PI_2 film on SiO_X (1 cycle ~ 1.3 nm). The profile of total polymer compositon (solid diamonds) is modified, especially in the second sputtering period. This is due to larger polydispersity of the protrusions and height distribution of the upper protrusion regions (exhibiting here both concave and convex shapes).

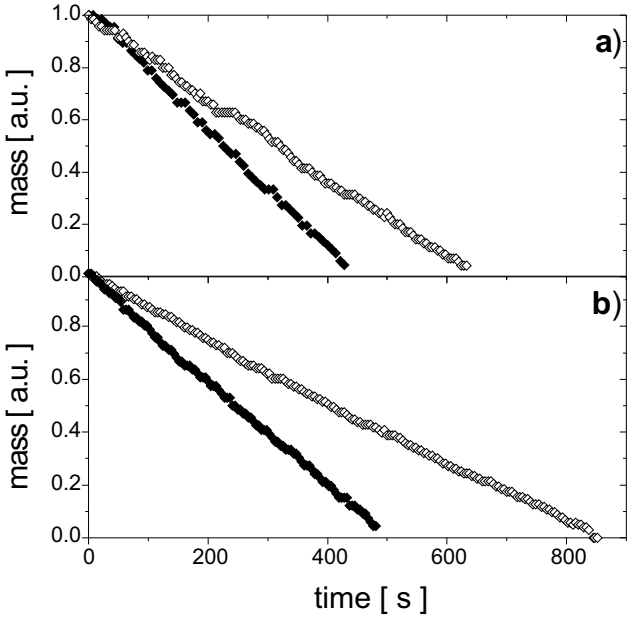

Fig. S3. Normalized weight of drying model layers plotted versus evaporation time. The layers composed of PS_1 (a), PI_1 (b) dissolved in toluene were cast onto CH_3-SAM (open diamonds) and COOH-SAM (solid diamonds). Stronger substrate effect (cf. Fig. 6(a)-(b)) was obtained for modified ambient conditions [56].